

NIKO-SEM
**P-Channel Logic Level Enhancement
Mode Field Effect Transistor**
PP5G7EA

PDFN 1x0.6

Halogen-Free & Lead-Free

PRODUCT SUMMARY

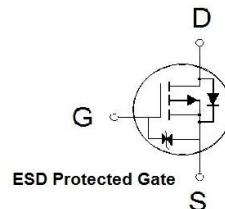
$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-30V	0.95Ω	-0.56A

**Features**

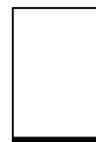
- Pb-Free, Halogen Free and RoHS compliant.
- Low $R_{DS(on)}$ to Minimize Conduction Losses.
- Ohmic Region Good $R_{DS(on)}$ Ratio.
- Optimized Gate Charge to Minimize Switching Losses.
- ESD Protection

Applications

- Protection Circuits Applications.
- Logic/Load Switch Circuits Applications.
- Space Limit & Smart Devices Applications.



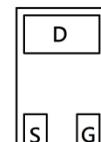
ESD Protected Gate



Top View



Side View



Bottom View

G: GATE
D: DRAIN
S: SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ²	I_D	-0.56	A
		-0.44	
Pulsed Drain Current ¹	I_{DM}	-1	A
Power Dissipation ³	P_D	0.54	W
		0.34	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		230	°C / W
			275	

¹Limited by maximum junction temperature.²Limited by package.³The Power dissipation is based on $R_{\theta JA}$ $t \leq 10s$ value.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-0.5	-0.96	-1.3	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 10\text{V}$			± 30	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			-10	
Drain-Source On-State Resistance ⁴	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -380\text{mA}$		0.7	0.95	Ω
		$V_{\text{GS}} = -2.5\text{V}, I_D = -100\text{mA}$		0.97	1.4	
Forward Transconductance ⁴	g_{fs}	$V_{\text{DS}} = -5\text{V}, I_D = -380\text{mA}$		1		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -15\text{V}, f = 1\text{MHz}$		51		pF
Output Capacitance	C_{oss}			18		
Reverse Transfer Capacitance	C_{rss}			9.2		
Total Gate Charge ⁵	Q_g	$V_{\text{GS}} = -4.5\text{V}, V_{\text{DS}} = -15\text{V}, I_D = -1\text{A}$		1.1		nC
Gate-Source Charge ⁵	Q_{gs}			0.1		
Gate-Drain Charge ⁵	Q_{gd}			0.6		
Turn-On Delay Time ⁵	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -15\text{V}, I_D \geq -380\text{mA}, V_{\text{GS}} = -4.5\text{V}, R_{\text{GEN}} = 6\Omega$		18		nS
Rise Time ⁵	t_r			28		
Turn-Off Delay Time ⁵	$t_{\text{d}(\text{off})}$			64		
Fall Time ⁵	t_f			46		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_s				-0.45	A
Forward Voltage ⁴	V_{SD}	$I_F = -380\text{mA}, V_{\text{GS}} = 0\text{V}$			-1.2	V
Reverse Recovery Time	t_{rr}	$I_F = -1\text{A}, dI/dt = 100 \text{ A}/\mu\text{s}$		26		nS
Reverse Recovery Charge	Q_{rr}			4		nC

⁴Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.

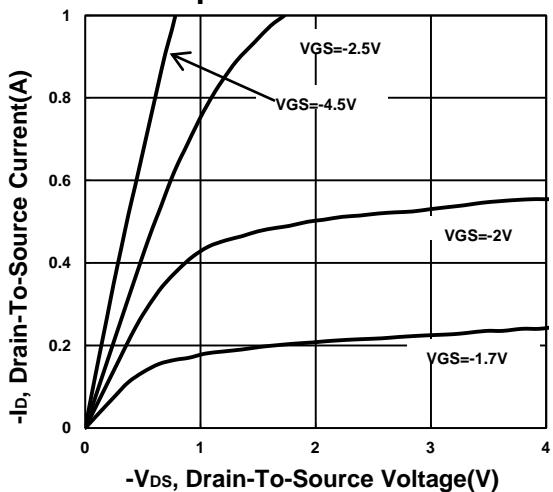
Independent of operating temperature.

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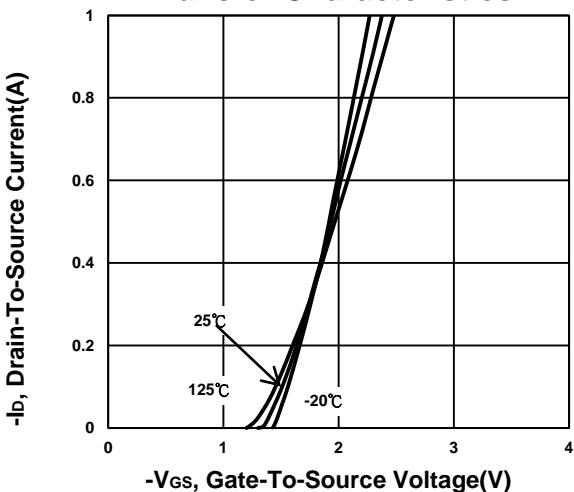
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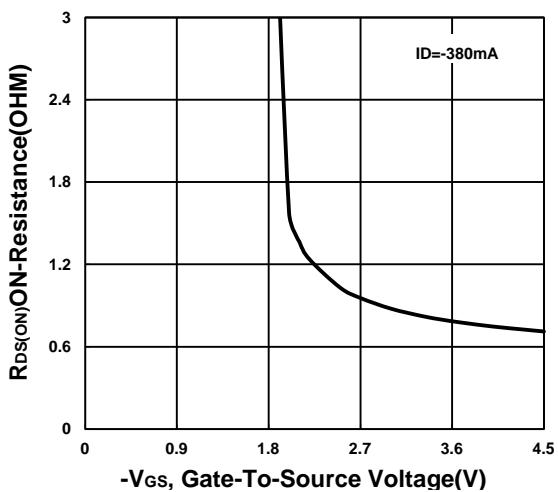
Output Characteristics



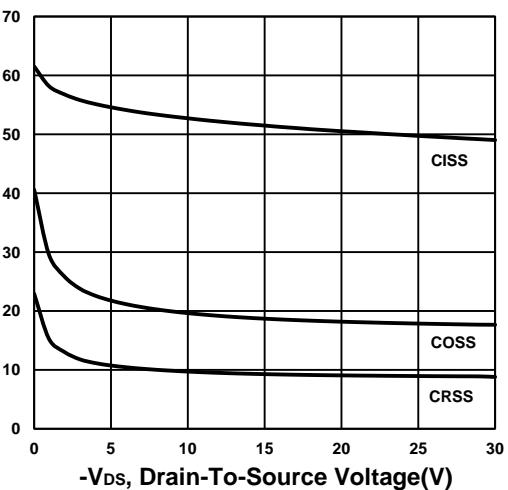
Transfer Characteristics



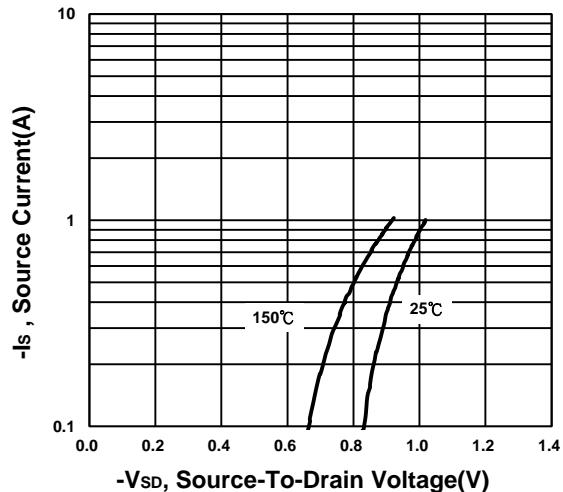
On-Resistance VS Gate-To-Source Voltage



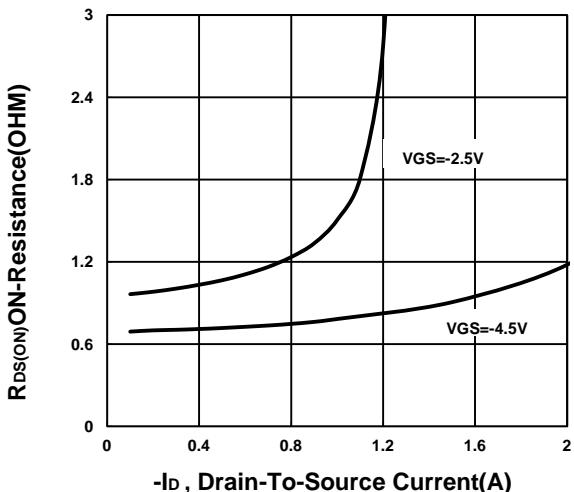
Capacitance Characteristic



Source-Drain Diode Forward Voltage



On-Resistance VS Drain Current

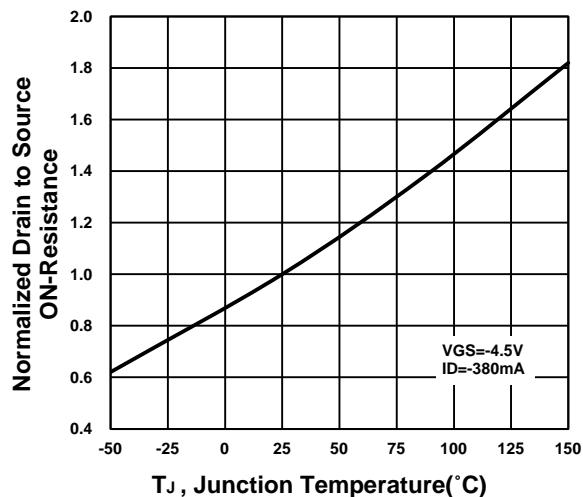


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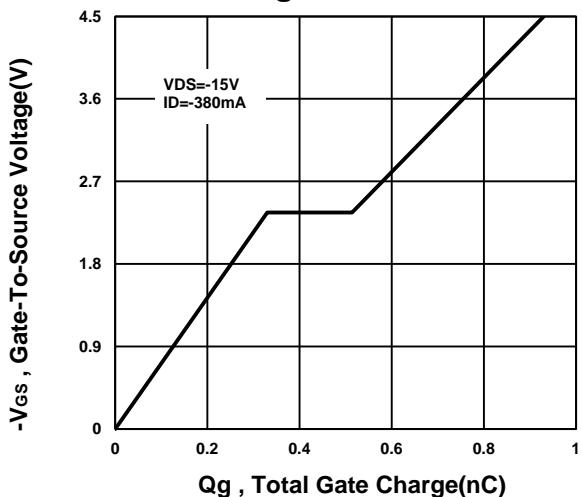
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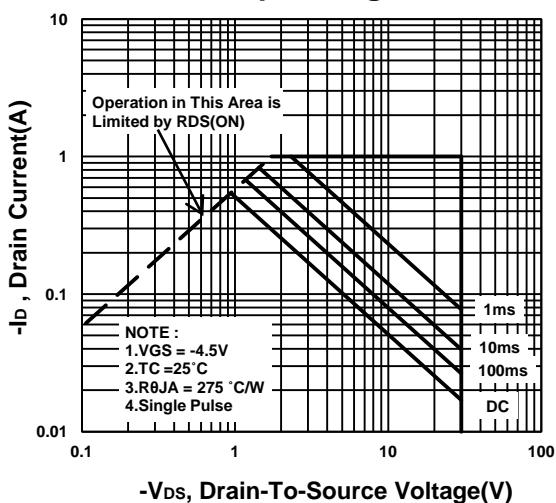
On-Resistance VS Temperature



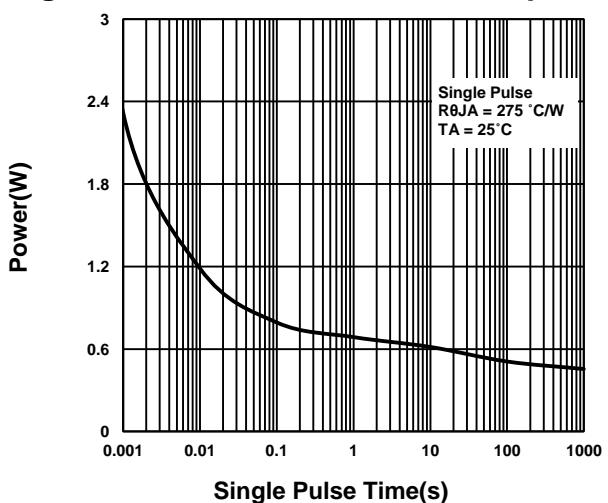
Gate charge Characteristics



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

